

<b>Notice of References Cited</b>	Application/Control No. 10/615,878		Applicant(s)/Patent Under Reexamination YUEH, WEN-HSIANG	
	Examiner Tadesse Hailu		Art Unit 2173	Page 1 of 2

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0234776	12-2003	Konishi, Isao	345/204
*	B	US-2005/0020320	01-2005	Lavelle et al.	455/569.2
*	C	US-2003/0125070	07-2003	Wagner et al.	455/550
*	D	US-2004/0155861	08-2004	Jackson III, Robert P.	345/156
*	E	US-2003/0137805	07-2003	Wu, Roger	361/686
*	F	US-7,019,737	03-2006	Asai et al.	345/211
*	G	US-6,944,480	09-2005	Tanaka et al.	455/566
*	H	US-6,877,099	04-2005	Sameshima et al.	713/324
*	I	US-6,781,635	08-2004	Takeda, Genyo	348/552
*	J	US-6,784,855	08-2004	Matthews et al.	345/1.1
*	K	US-6,421,232	07-2002	Sallam, Hussein	361/681
*	L	US-6,574,488	06-2003	Oba et al.	455/566
*	M	US-2004/0005914	01-2004	Dear, Jean Paul	455/563

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

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	U	
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10/615,878

Applicant(s)/Patent Under  
Reexamination  
YUEH, WEN-HSIANG

Examiner

Tadesse Hailu

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2173

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,757,354	05-1998	Kawamura, Hiroshi	345/656
*	B	US-6,460,109	10-2002	Kaply et al.	710/316
*	C	US-6,760,010	07-2004	Webb, Geoffrey J. H.	345/168
*	D	US-6,493,734	12-2002	Sachs et al.	715/526
*	E	US-6,052,120	04-2000	Nahi et al.	715/700
*	F	US-2004/0010599	01-2004	Otobe, Takashi	709/228
*	G	US-2004/0061706	04-2004	Cronin et al.	345/629
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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